Special Issue

Computer Vision and Sensing Technologies for Industrial Quality Inspection

Message from the Guest Editors

This special issue calls for research papers through use cases of artificial intelligence techniques and showcases the need to optimize algorithms, inference frameworks, and hardware accelerators to obtain good performance in quality inspection. It mainly focuses on computer vision and sensing technologies for industrial quality inspection, including, but not limited to, imaging techniques, image processing methods, vision systems, and system optimization. Industrial inspection papers are also welcome, such as quality inspection with machine learning and data-driven methods. Both review articles and original research papers are sought in this special issue.

Guest Editors

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Prof. Dr. Cheng-Hsiung Hsieh

Prof. Dr. Hsin-Chieh Wu

Deadline for manuscript submissions

closed (25 July 2024)

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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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